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APPLICANT Roumiana TSENKOVA		
FILING DATE November 30, 2001	GROUP Unassigned	

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

U.S. PATENT DOCUMENTS						
Examiner Initials	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication (MM-DD-YYYY)		
	Number	Kind Code (if known)				

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Foreign Patent Document		Country	Date of Publication (MM-DD-YYYY)	Translation	
	Number	Kind Code (if known)			Yes	no
MY/LC	SU1832008		Soviet Union (w/English abstract)	08-07-1993		
MY/LC	JP4-47254		Japan (w/English abstract)	02-17-1992		
MY/LC	JP7-151677		Japan (w/English abstract)	06-16-1995		
MY/LC	JP2000-9637		Japan (w/English abstract)	01-14-2000		
MY/LC	JP7-306139		Japan (w/English abstract)	11-21-1995		
MY/LC	JP2000-146832		Japan (w/English abstract)	05-26-2000		

NON PATENT LITERATURE DOCUMENTS	
Examiner Initials	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
MY/LC	K. MURAYAMA et al, "Raw Milk Near Infrared Spectra for Mastitis Diagnosis", Dai 16 Kai Hihaki Keisoku Symposium Koen Yoshishuu (Japan) Shadan Hojin Nippon Shokuhin Kagaku Kogakukaied., November 8, 2000, pp. 184-189
MY/LC	R.N. TSENKOVA et al, "Near-Infrared Spectroscopy of Individual Cow Milk as a Means for Automated Monitoring of Udder Health and Milk Quality", Proc. 3 <sup>rd</sup> . Int. Dairy Housing Conf., (1994) pp. 82-91
MY/LC	R. TSENKOVA, "Near Infrared Spectroscopy: A Uniform Measuring Technology For A Sustainable Dairy Production System", J. Near. Infrared Spectroscopy, No. 6, (1998), pp. A45-A51.
MY/LC	Prospects for Automatic Milking, (1992), EAAP publ. No. 65
MY/LC	R. TSENKOVA et al, "Near Infrared Spectroscopy for Biomonitoring: Cow Milk Composition Measurement in a Spectral Region from 1,100 to 2,400 Nanometers <sup>1</sup> ", J. Anim. Sci., Vol 78, No. 3, March 31, 2000, pp. 515-522
MY/LC	Optronics (Japan), No. 205, (1999), pp. 211-214, (especially, Chapter 2.2)
Examiner Signature	<div>Matthew Krue</div>
	<div>Date Considered</div> <div>7/10/2003</div>

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